Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,478	IDOTA ET AL.
Examiner	Art Unit
Anh D. Mai	2814

	SEARCHED		
Class	Subclass	Date	Examiner
438	202; 207 234-235 309; 312 322	3/14/2005	A.M
			,

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	235; 309 312	3/15/05	A.M

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (all) * Inventors * CCLS * bipolar transistor and lateral and (etch mask) * SIGE HBT	3/15/2005	A.M
IEEE explore (web): HBT and SiGe	3/15/2005	A.M
JPO (web): Fi/F term 5F003; 5F082	3/15/2005	A.M